



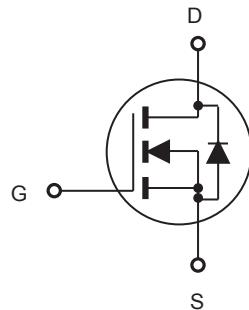
CEP740A/CEB740A CEF740A

N-Channel Enhancement Mode Field Effect Transistor

FEATURES

Type	V _{DSS}	R _{DS(ON)}	I _D	@V _{GS}
CEP740A	400V	0.55Ω	10A	10V
CEB740A	400V	0.55Ω	10A	10V
CEF740A	400V	0.55Ω	10A ^d	10V

- Super high dense cell design for extremely low R_{DS(ON)}.
- High power and current handing capability.
- Lead-free plating ; RoHS compliant.



ABSOLUTE MAXIMUM RATINGS T_C = 25°C unless otherwise noted

Parameter	Symbol	Limit		Units
		TO-220/263	TO-220F	
Drain-Source Voltage	V _{DS}	400		V
Gate-Source Voltage	V _{GS}	±30		V
Drain Current-Continuous @ T _C = 25°C @ T _C = 100°C	I _D	10 7.4	10 ^d 7.4 ^d	A
Drain Current-Pulsed ^a	I _{DM} ^e	40	40 ^d	A
Maximum Power Dissipation @ T _C = 25°C - Derate above 25°C	P _D	150 1	48 0.55	W W/°C
Single Pulsed Avalanche Energy ^h	E _{AS}	250		mJ
Single Pulsed Avalanche Current ^h	I _{AS}	10		A
Operating and Store Temperature Range	T _{J,T_{stg}}	-55 to 175		°C

Thermal Characteristics

Parameter	Symbol	Limit		Units
Thermal Resistance, Junction-to-Case	R _{θJC}	1	3.1	°C/W
Thermal Resistance, Junction-to-Ambient	R _{θJA}	62.5	65	°C/W



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Electrical Characteristics $T_C = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min	Typ	Max	Units
Off Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}} = 0\text{V}, I_D = 250\mu\text{A}$	400			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{\text{DS}} = 400\text{V}, V_{\text{GS}} = 0\text{V}$		1		μA
Gate Body Leakage Current, Forward	I_{GSSF}	$V_{\text{GS}} = 30\text{V}, V_{\text{DS}} = 0\text{V}$		100		nA
Gate Body Leakage Current, Reverse	I_{GSSR}	$V_{\text{GS}} = -30\text{V}, V_{\text{DS}} = 0\text{V}$		-100		nA
On Characteristics^b						
Gate Threshold Voltage	$V_{\text{GS}(\text{th})}$	$V_{\text{GS}} = V_{\text{DS}}, I_D = 250\mu\text{A}$	2		4	V
Static Drain-Source On-Resistance	$R_{\text{DS}(\text{on})}$	$V_{\text{GS}} = 10\text{V}, I_D = 5\text{A}$		0.44	0.55	Ω
Dynamic Characteristics^c						
Input Capacitance	C_{iss}	$V_{\text{DS}} = 25\text{V}, V_{\text{GS}} = 0\text{V}, f = 1.0 \text{ MHz}$		1610		pF
Output Capacitance	C_{oss}			135		pF
Reverse Transfer Capacitance	C_{rss}			5		pF
Switching Characteristics^c						
Turn-On Delay Time	$t_{\text{d}(\text{on})}$	$V_{\text{DD}} = 320\text{V}, I_D = 10\text{A}, V_{\text{GS}} = 10\text{V}, R_{\text{GEN}} = 9.1\Omega$		19	38	ns
Turn-On Rise Time	t_r			4	8	ns
Turn-Off Delay Time	$t_{\text{d}(\text{off})}$			34	68	ns
Turn-Off Fall Time	t_f			3	6	ns
Total Gate Charge	Q_g	$V_{\text{DS}} = 320\text{V}, I_D = 10\text{A}, V_{\text{GS}} = 10\text{V}$		24	31	nC
Gate-Source Charge	Q_{gs}			6		nC
Gate-Drain Charge	Q_{gd}			4		nC
Drain-Source Diode Characteristics and Maximum Ratings						
Drain-Source Diode Forward Current	I_S^f				10	A
Drain-Source Diode Forward Voltage ^b	V_{SD}^g	$V_{\text{GS}} = 0\text{V}, I_S = 10\text{A}$			1.5	V
Notes : a.Repetitive Rating : Pulse width limited by maximum junction temperature . b.Pulse Test : Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$. c.Guaranteed by design, not subject to production testing. d.Limited only by maximum temperature allowed . e.Pulse width limited by safe operating area . f.Full package $I_{\text{S}(\text{max})} = 5.9\text{A}$. g.Full package V_{SD} , test condition $I_S = 5.9\text{A}$. h.L = 5mH, $ A_G = 10\text{A}$, $V_{\text{DP}} = 50\text{V}$, $R_G = 25\Omega$, Starting $T_J = 25^\circ\text{C}$						

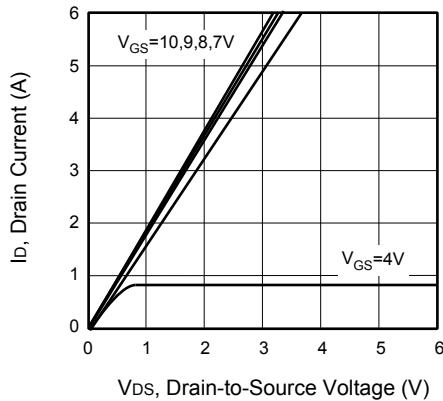


Figure 1. Output Characteristics

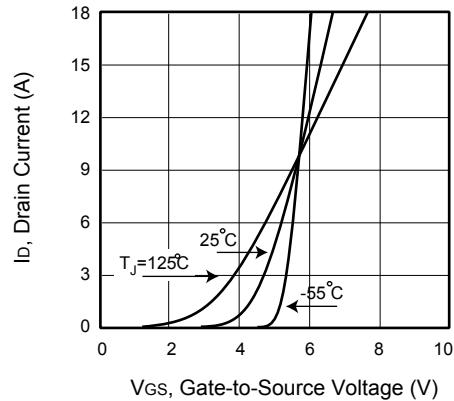


Figure 2. Transfer Characteristics

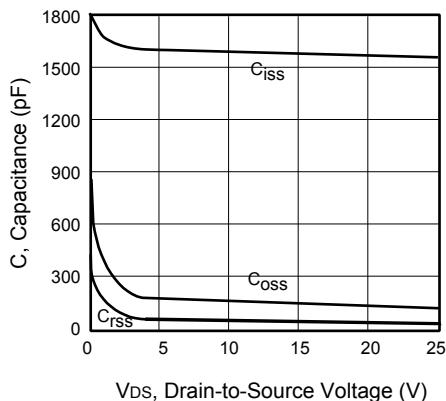


Figure 3. Capacitance

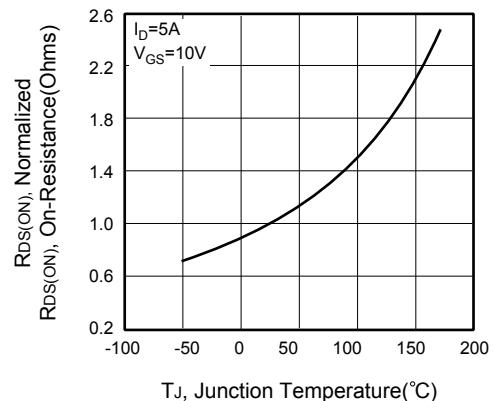


Figure 4. On-Resistance Variation with Temperature

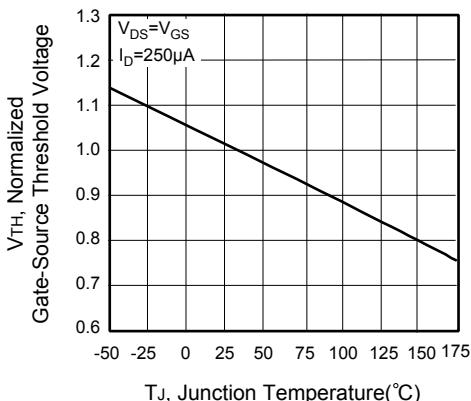


Figure 5. Gate Threshold Variation with Temperature

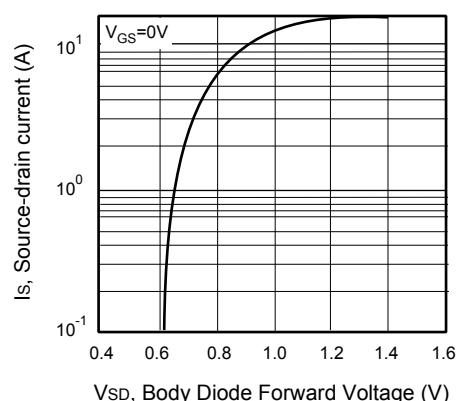


Figure 6. Body Diode Forward Voltage Variation with Source Current



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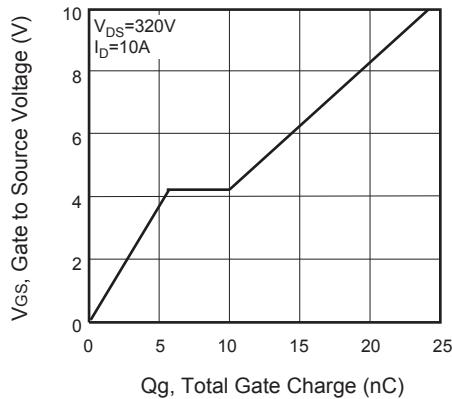


Figure 7. Gate Charge

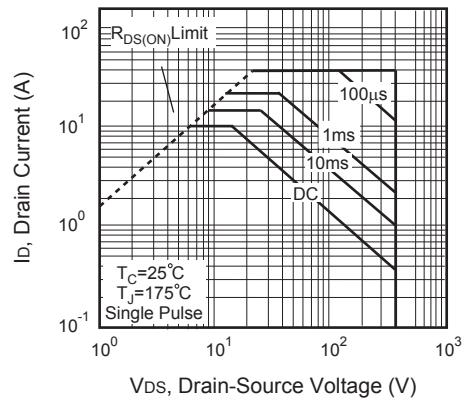


Figure 8. Maximum Safe Operating Area

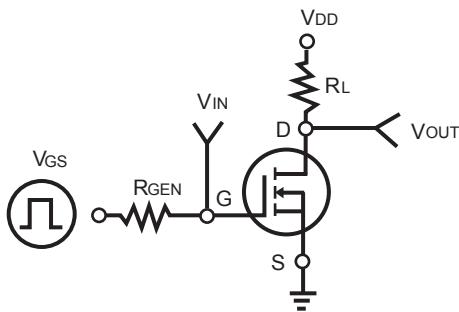


Figure 9. Switching Test Circuit

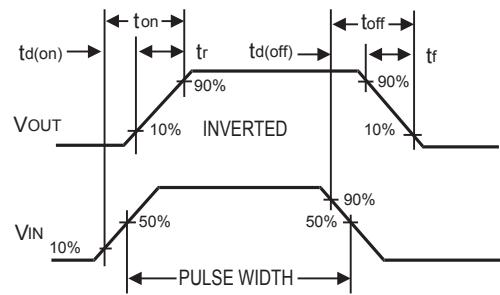


Figure 10. Switching Waveforms

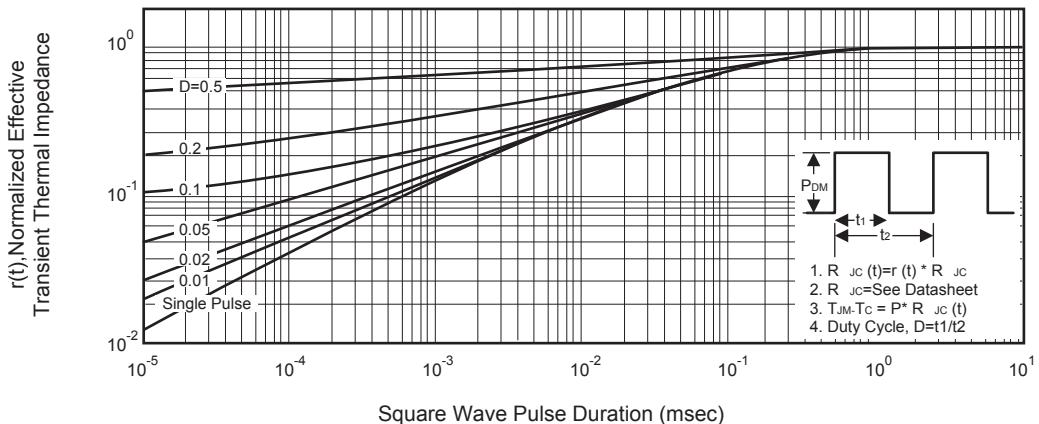


Figure 11. Normalized Thermal Transient Impedance Curve